

<b>Issue Classification</b> 	Application/Control No. 10/789,243	Applicant(s)/Patent under Reexamination YANG ET AL.
	Examiner Devona E. Faulk	Art Unit 2615

ISSUE CLASSIFICATION											
ORIGINAL			INTERNATIONAL CLASSIFICATION								
CLASS		SUBCLASS	CLAIMED			NON-CLAIMED					
381		77	H	4	B	3	/00	/			
CROSS REFERENCES						H	4	B	5	/00	/
CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)					H	4	R	3	/00	/
381	79	111	116			G	10	S	15	/00	/
367	92	138				H	4	B	1	/02	/
										/	/
										/	/
7/31/96 Devona E. Faulk (Assistant Examiner) (Date)		VIVIAN CHIN SUPERVISORY PATENT EXAMINER TECHNOLOGY CENTER 2600 (Primary Examiner) (Date)			Total Claims Allowed: 11						
(Legal Instruments Examiner) 8/5/96 (Date)		O.G. Print Claim(s) 86						O.G. Print Fig. 4			

<input type="checkbox"/> Claims renumbered in the same order as presented by applicant		<input type="checkbox"/> CPA		<input type="checkbox"/> T.D.		<input type="checkbox"/> R.1.47	
Final	Original	Final	Original	Final	Original	Final	Original
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5	1	35	65	10	95	125	155
6	1	36	66	11	96	126	156
7	1	37	67	12	97	127	157
8	1	38	68	13	98	128	158
9	1	39	69	14	99	129	159
10	1	40	70	15	100	130	160
11	1	41	71	16	101	131	161
12	1	42	72	17	102	132	162
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14	1	44	74	19	104	134	164
15	1	45	75	20	105	135	165
16	1	46	76	21	106	136	166
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19	1	49	79	24	109	139	169
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22	1	52	82	27	112	142	172
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24	1	54	84	29	114	144	174
25	1	55	85	30	115	145	175
26	1	56	86	1	116	146	176
27	1	57	87	2	117	147	177
28	1	58	88	3	118	148	178
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